

# Search Notes



Application/Control No.

10/615,725

Examiner

Henry K. Choe

Applicant(s)/Patent under  
Reexamination

QUADIR ET AL.

Art Unit

2817

## SEARCHED

Class	Subclass	Date	Examiner
330	308	3/15/06	H.C.
"	311	"	"
"	310	"	"
"	98	3/16/06	"
"	150	"	"

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Full search (East) see attachment		
NPL (IEEE) see attachment		